

Matthias Schaller

List of Publications by Year in descending order

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7
papers

54
citations

1684188

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1720034

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7
all docs

7
docs citations

7
times ranked

62
citing authors

| # | ARTICLE | IF | CITATIONS |
|---|---|-----|-----------|
| 1 | Chemical Repair of Plasma Damaged Porous Ultra Low- $\hat{\rho}$ SiOCH Film Using a Vapor Phase Process. Journal of the Electrochemical Society, 2010, 157, H1140. | 2.9 | 16 |
| 2 | Investigation of physical and chemical property changes of ultra low- $\hat{\rho}$ SiOCH in aspect of cleaning and chemical repair processes. Microelectronic Engineering, 2010, 87, 457-461. | 2.4 | 9 |
| 3 | Improved characterization of Fourier transform infrared spectra analysis for post-etched ultra-low- $\hat{\rho}$ SiOCH dielectric using chemometric methods. Journal of Vacuum Science & Technology B, 2009, 27, 521-526. | 1.3 | 7 |
| 4 | Restoring Processes at Carbon Depleted Ultralow- $\hat{\rho}$ Surfaces. Journal of Physical Chemistry A, 2011, 115, 8282-8287. | 2.5 | 7 |
| 5 | Surface Energy and Wetting Behaviour of Plasma Etched Porous SiCOH Surfaces and Plasma Etch Residue Cleaning Solutions. Solid State Phenomena, 2009, 145-146, 319-322. | 0.3 | 6 |
| 6 | Silylation of silicon bonded hydroxyl groups by silazanes and siloxanes containing an acetoxy group. N-trimethylsilylimidazole vs. dimethyldiacetoxysilane. Computational and Theoretical Chemistry, 2012, 991, 44-47. | 2.5 | 5 |
| 7 | How to evaluate surface free energies of dense and ultra low- $\hat{\rho}$ dielectrics in pattern structures. Microelectronic Engineering, 2011, 88, 680-683. | 2.4 | 4 |